TOSHIBA TC551402J-22,-25

#### TOSHIBA MOS DIGITAL INTEGRATED CIRCUIT SILICON GATE CMOS

# 4,194,304-WORD BY 1-BIT/1,048,576-WORD BY 4-BIT CMOS STATIC RAM

The TC551402J is a 4,194,304-bit high speed static random access memory (SRAM), it is possible to change the organization between 4,194,304 words by 1 bit and 1,048,576 words by 4 bits. Fabricated using CMOS technology and advanced circuit techniques to provide high speed, it operates from a single <u>5 V</u> power supply. Chip enable (CE) can be used to place the device in a low-power mode, and output enable (OE) provides fast memory access. This device is well suited to cache memory applications where high-speed access and highspeed storage are required. All inputs and outputs are isolated and directly TTL compatible. The TC551402J is available in a plastic 32-pin SOJ package (400 mil width) for high density surface assembly.

#### **FEATURES**

- Fast access time (the following are maximum values) TC551402J-22: 22 ns TC551402J-25: 25 ns Single power supply voltage: TC551402J-22:  $5V\pm5\%$ TC551402J-25:  $5V\pm10\%$
- Low-power dissipation

(the following are maximum values)
Operating: 180 mA (22 ns type)
Operating: 160 mA (25 ns type)
Standby: 10 mA (all devices)

- Fully static operation
- All inputs and outputs are TTL compatible Separate inputs and outputs ( $\times 1$  Mode) Common data input and output (×4 Mode) Output buffer control using OE

ROW DECODER

**BLOCK DIAGRAM** 

Package: SOJ32-P-400-1.27A (Weight: 1.22 g typ)

MEMORY CELL

ARRAY

 $1024 \times 1024 \times 4$ 

(4,194,304)

#### PIN ASSIGNMENT

A0 to A21

I/O1 to I/O4

D

Q

CE

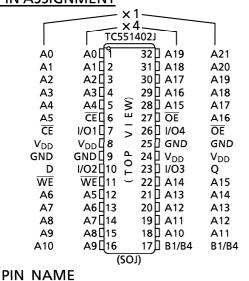
WE

OE

 $V_{DD}$ 

GND

B1/B4



Address Inputs

Data Input

Ground

Bit Function

Data Output

Data Inputs/Outputs

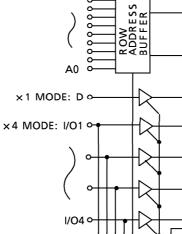
Chip Enable Input

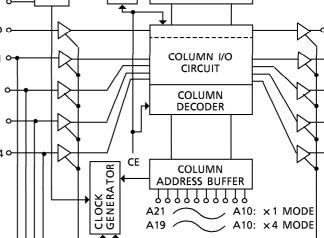
Write Enable Input

Output Enable Input Power ( + 5 V)











CE o CE WE o OF 9 CE

961001EBA1

-• ν<sub>DD</sub>

⊸ GND

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#### **MAXIMUM RATINGS**

SYMBOL	ITEM	RATING	UNIT
V <sub>DD</sub>	Power Supply Voltage	- 0.5 to 7.0	V
V <sub>IN</sub>	Input Terminal Voltage	- 2.0* to 7.0	V
V <sub>I/O</sub>	I/O Terminal Voltage	- 0.5* to V <sub>DD</sub> + 0.5	V
V <sub>OUT</sub>	Output Terminal Voltage	– 0.5* to V <sub>DD</sub> + 0.5	V
P <sub>D</sub>	Power Dissipation	1.0	W
Tsolder	Soldering Temperature (10 s)	260	°C
Tstrg	Storage Temperature	- 65 to 150	°C
Topr	Operating Temperature	- 10 to 85	°C

\*: - 3 V with a pulse width of 10 ns

## <u>DC RECOMMENDED OPERATING CONDITIONS</u> (Ta = $0^{\circ}$ to $70^{\circ}$ C)

SYMBOL	PARAMETER		MIN	TYP	TYP	UNIT
V	Power Supply Voltage	-22	4.75	5.0	5.25	V
$V_{\mathrm{DD}}$	Power Supply Voltage -25	-25	4.5	5.0	5.5	ľ
V <sub>IH</sub>	Input High Voltage		2.2	-	V <sub>DD</sub> + 0.5	V
V <sub>IL</sub>	Input Low Voltage		- 0.5 *	-	0.8	V

\*: - 3 V with a pulse width of 10 ns

## <u>DC CHARACTERISTICS</u> (Ta = $0^{\circ}$ to $70^{\circ}$ C, -22 : $V_{DD}$ = $5V \pm 5\%$ , -25 : $V_{DD}$ = $5V \pm 10\%$ )

SYMBOL	PARAMETER	TEST CONDITION		MIN	TYP	TYP	UNIT
I <sub>IL</sub>	Input Leakage Current	$V_{IN} = 0 V \text{ to } V_{DD}$		ı	ı	± 10	μΑ
I <sub>OH</sub>	Output High Current	V <sub>OH</sub> = 2.4 V		- 4	ı	ı	mA
I <sub>OL</sub>	Output Low Current	V <sub>OL</sub> = 0.4 V		8	ı	ı	mA
I <sub>LO</sub>	Output Leakage Current	$\overline{CE} = V_{IH} \text{ or } \overline{WE} = V_{IL} \text{ or } \overline{OE} = V_{IH}, V_{OUT} = 0 \text{ V}$ to $V_{DD}$		ı	ı	± 10	μΑ
	tcycle = Minimum Cycle, $\overline{CE} = V_{ L}$ , -22		ı	ı	180	A	
I <sub>DDO</sub>	Operating Current	lout = 0 mA, Other Inputs = V <sub>IH</sub> or V <sub>IL</sub> -25		-	ı	160	mA
I <sub>DDS1</sub>		$\overline{CE} = V_{IH}$ $Other Inputs = V_{IH} \text{ or } V_{IL}$ $\overline{CE} = V_{DD} - 0.2 \text{ V}$ $Other Inputs = V_{DD} - 0.2 \text{ V or } 0.2 \text{ V}$		-	-	30	
I <sub>DDS2</sub>	Standby Current			_	_	10	mA

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### <u>CAPACITANCE</u> (Ta = $25^{\circ}$ C, f = 1.0 MHz)

SYMBOL	PARAMETER	TEST CONDITION	MAX	UNIT
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = GND	8	pF
C <sub>I/O</sub> , C <sub>OUT</sub>	D <sub>OUT</sub> Capacitance	V <sub>OUT</sub> = GND	8	pF

Note: This parameter is periodically sampled and is not 100% tested.

#### **TRUTH TABLE**

	MODE	B1/B4	CE	ŌĒ	WE	I/O	POWER
	Read	Н	L	L	Н	Dout	I <sub>DDO</sub>
×1 MODE	Write	Н	L	×	L	Din	I <sub>DDO</sub>
	Output Disabled	Н	L	Н	Н	High - Z	I <sub>DDO</sub>
	Standby	Н	Н	×	×	High - Z	I <sub>DDS</sub>
	Read	L	L	L	Н	Dout	I <sub>DDO</sub>
×4	Write	L	L	×	L	Din	I <sub>DDO</sub>
MODE	Output Disabled	L	L	Н	Н	High - Z	I <sub>DDO</sub>
	Standby	L	Н	×	× (/TT)	High - Z	I <sub>DDS</sub>

X: "H" or "L"

TC551402J is possible to change the organization of bit mode between 4M words by one bit and 1M words by four bits with input level of pin condition B1/B4.

"4M  $\times$  1 Mode" is performed on when pin B1/B4 is held on "V $_{IH}$  level". On the other hand "1M  $\times$  4 Mode" is requires B1/B4 be connected to "V $_{IL}$  level".

Input level of B1/B4 condition must be set at the same time of power on. Any of change of input level B1/B4, high or low, is prohibited after power on.

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<u>AC CHARACTERISTICS</u> (Ta =  $0^{\circ}$  to  $70^{\circ}$ C (Note 4), -22 :  $V_{DD}$  =  $5V \pm 5\%$ , -25 :  $V_{DD}$  =  $5V \pm 10\%$ )

**READ CYCLE** 

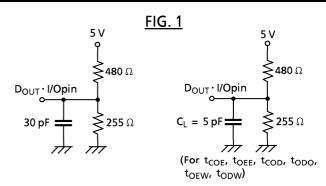
SYMBOL	PARAMETER	TC551402J-22		TC551402J-25		LINUT
STIVIBUL	PARAIVIETER	MIN	MAX	MIN	MAX	UNIT
t <sub>RC</sub>	Read Cycle Time	22	-	25	-	
t <sub>ACC</sub>	Address Access Time	_	22	_	25	
t <sub>CO</sub>	Chip Enable Access Time	_	22	_	25	
t <sub>OE</sub>	Output Enable Access Time	_	12	_	12	
t <sub>COE</sub>	Output Enable Time from Chip Enable	5	_	5	-	
t <sub>COD</sub>	Output Disable Time from Chip Enable	-	10	-	10	ns
t <sub>OEE</sub>	Output Enable Time from Output Enable	1	-	1	-	
t <sub>ODO</sub>	Output Disable Time from Output Enable	-	10	-	10	
t <sub>OH</sub>	Output Data Hold Time from Address Change	5	_	5	_	
t <sub>PU</sub>	Chip Selection to Power Up Time	0	_	0	_	
t <sub>PD</sub>	Chip Deselection to Power Down Time	_	22	_	25	

### **WRITE CYCLE**

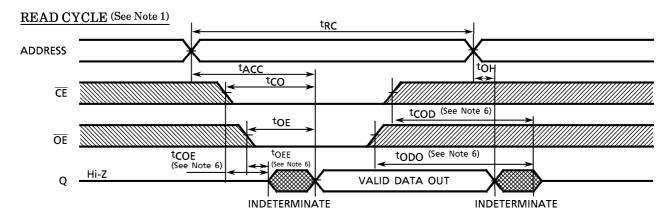
CVMPO	DADAMETED	TC5514	TC551402J-22		TC551402J-25		
SYMBOL	PARAMETER	MIN	MAX	MIN	MAX	UNIT	
t <sub>WC</sub>	Write Cycle Time	22	-	25	-		
$t_WP$	Write Pulse Width	13	_	13	_		
t <sub>AW</sub>	Address Valid to End of Write	20	_	20	_		
t <sub>CW</sub>	Chip Enable to End of Write	20	_	20	-	-	
t <sub>AS</sub>	Address Setup Time	0	_	0	-		
$t_WR$	Write Recovery Time	0	_	0	_	ns	
t <sub>OEW</sub>	Output Enable Time from Write Enable	1	-	1	-		
t <sub>ODW</sub>	Output Disable Time from Write Enable	-	10	_	10		
t <sub>DS</sub>	Data Setup Time	12	-	12	-		
t <sub>DH</sub>	Data Hold Time	0	_	0	_		

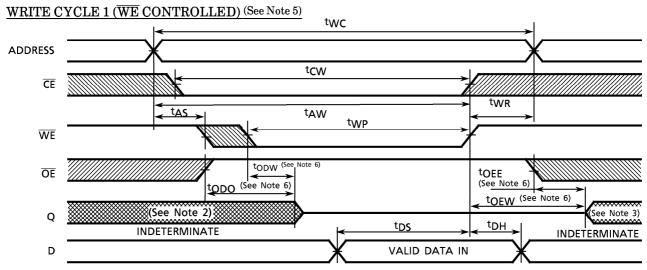
## **AC TEST CONDITION**

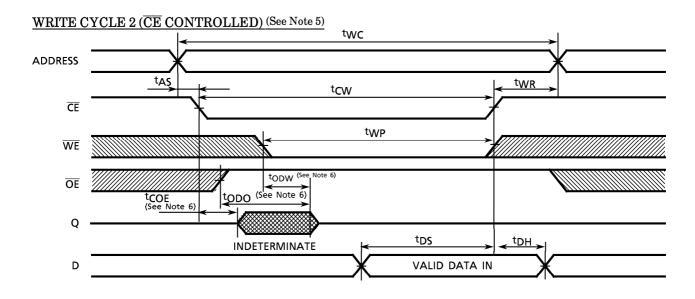
Input Pulse Levels	3.0 V, 0.0 V
Input Pulse Rise and Fall Time	3 ns
Input Timing Measurement Reference Levels	1.5 V
Output Timing Measurement Reference Levels	1.5 V
Output Load	Fig. 1



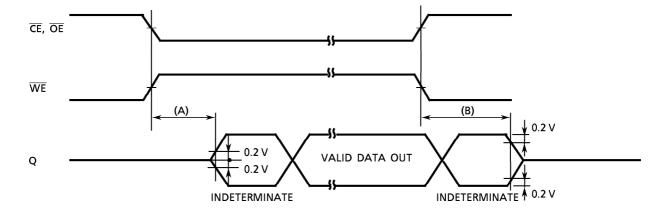
#### **TIMING DIAGRAMS**







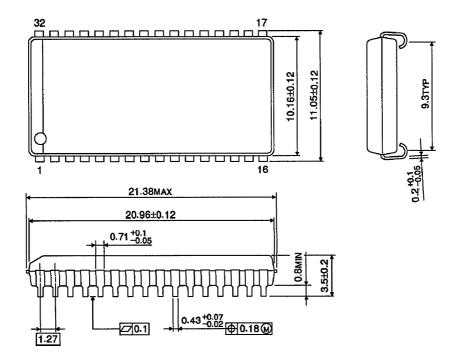
- Note: (1) Operating temperature (Ta) is guaranteed for transverse air flow exceeding 400 linear feet per minute.
  - (2) WE remains HIGH for Read Cycle.
  - (3) If  $\overline{\text{CE}}$  goes LOW coincident with or after  $\overline{\text{WE}}$  goes LOW, the outputs will remain at high impedance.
  - (4) If  $\overline{\text{CE}}$  goes HIGH coincident with or before  $\overline{\text{WE}}$  goes HIGH, the outputs will remain at high impedance.
  - (5) If  $\overline{OE}$  is HIGH during the write cycle, the outputs will remain at high impedance.
  - (6) The parameters specified below are measured using the load shown in Fig. 1.
    - (A)  $t_{COE}$ ,  $t_{OEE}$ ,  $t_{OEW}$  ..... Output Enable Time
    - (B) t<sub>COD</sub>, t<sub>ODO</sub>, t<sub>ODW</sub> ..... Output Disable Time



### **PACKAGE DIMENSIONS**

Plastic SOJ (SOJ32-P-400-1.27A)

Units in mm



Weight: 1.22 g (typ)